

C1206C621G2TACTU

Aliases (C1206C621G2TAC7800) SMD Comm X8G HT150C, Ceramic, 620 pF, 2%, 200 VDC, X8G, SMD, MLCC, High Temperature, Ultra-Stable, 1206, 1.5 mm



General Information		
Series	SMD Comm X8G HT150C	
Style	SMD Chip	
Description	SMD, MLCC, High Temperature, Ultra-Stable	
Features	High Temperature, Ultra-Stable	
RoHS	Yes	
Termination	Tin	
Marking	No	
AEC-Q200	No	
Typical Component Weight	15 mg	
Shelf Life	78 Weeks	
MSL	1	

	Dimensions
1206	Chip Size
3.2mm +/-0.2mm	L
1.6mm +/-0.2mm	W
0.78mm +/-0.10mm	T
1.5mm MIN	S
0.5mm +/-0.25mm	В
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W	1.6mm +/-0.2mm	Tolerance	2%
Т	0.78mm +/-0.10mm	Voltage DC	200 VDC
S	1.5mm MIN	Dielectric Withstanding Voltage	500 VDC
В	0.5mm +/-0.25mm	Temperature Range	-55/+150°C
		Temp. Coefficient	X8G
Packaging Specifications		Capacitance Change with	30 ppm/C, 1MegaHz 1.0Vrms
Packaging	T&R, 180mm, Plastic Tape	Reference to +25°C and 0 VDC Applied (TCC)	
Packaging Quantity	4000	Dissipation Factor	0.1% 1 MHz 1.0Vrms
		Aging Rate	0% Loss/Decade Hour: Referee

Specifications		
Capacitance	620 pF	
Measurement Condition	1 MHz 1.0Vrms	
Tolerance	2%	
Voltage DC	200 VDC	
Dielectric Withstanding Voltage	500 VDC	
Temperature Range	-55/+150°C	
Temp. Coefficient	X8G	
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	30 ppm/C, 1MegaHz 1.0Vrms	
Dissipation Factor	0.1% 1 MHz 1.0Vrms	
Aging Rate	0% Loss/Decade Hour: Referee Time is 1000 Hours	
Insulation Resistance	100 GOhms	

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